

**Development of monocrystal Silicon Fibers
by μ -Pd technique**

Mauro Tonelli

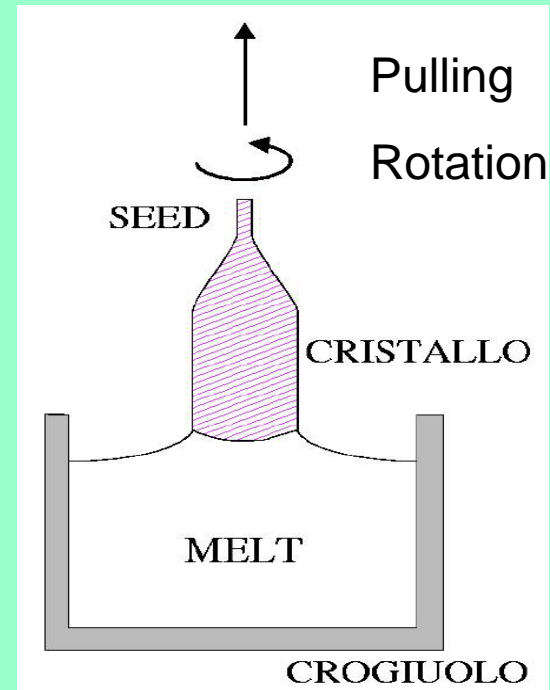
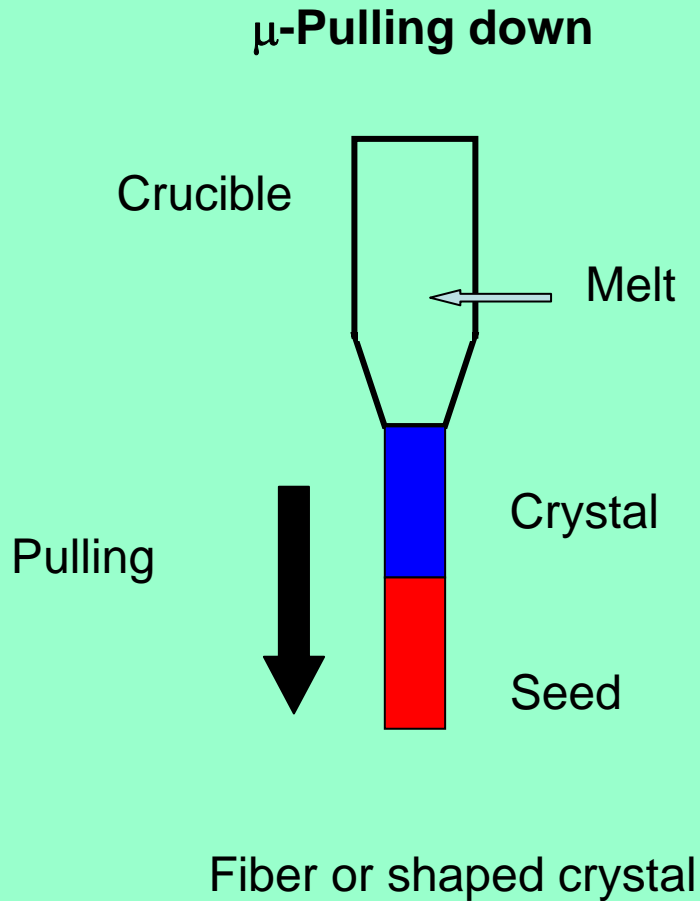
Dipartimento di Fisica-Sez. INFN-Pisa-Italy

“Crystal Group” Virgo Pisa

People

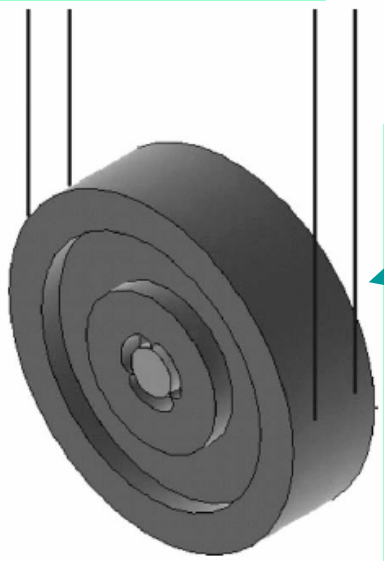
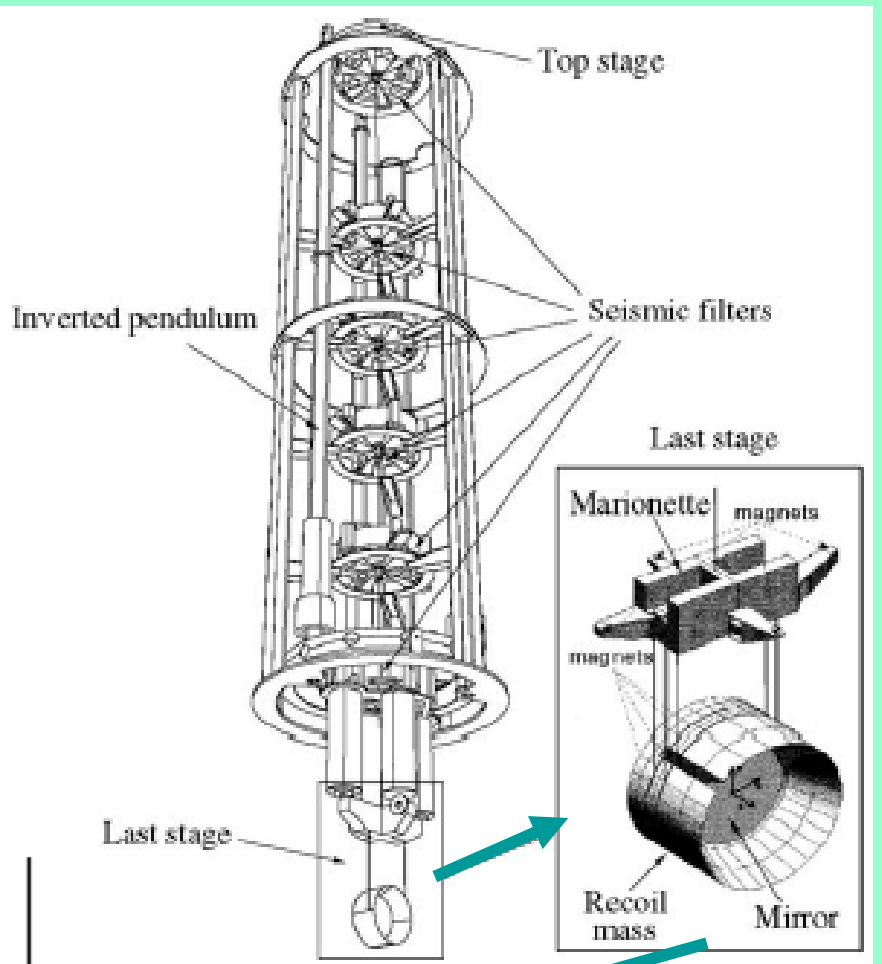
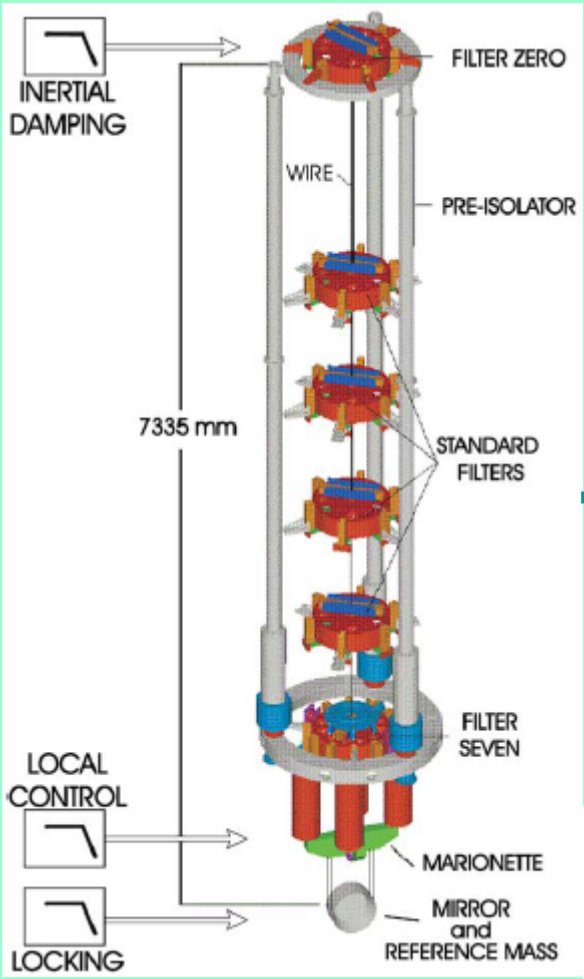
- Permanent staff: **A. Toncelli, M. Tonelli**
- Fellowship: **Zhitai Jia**

Crystal growth by melt



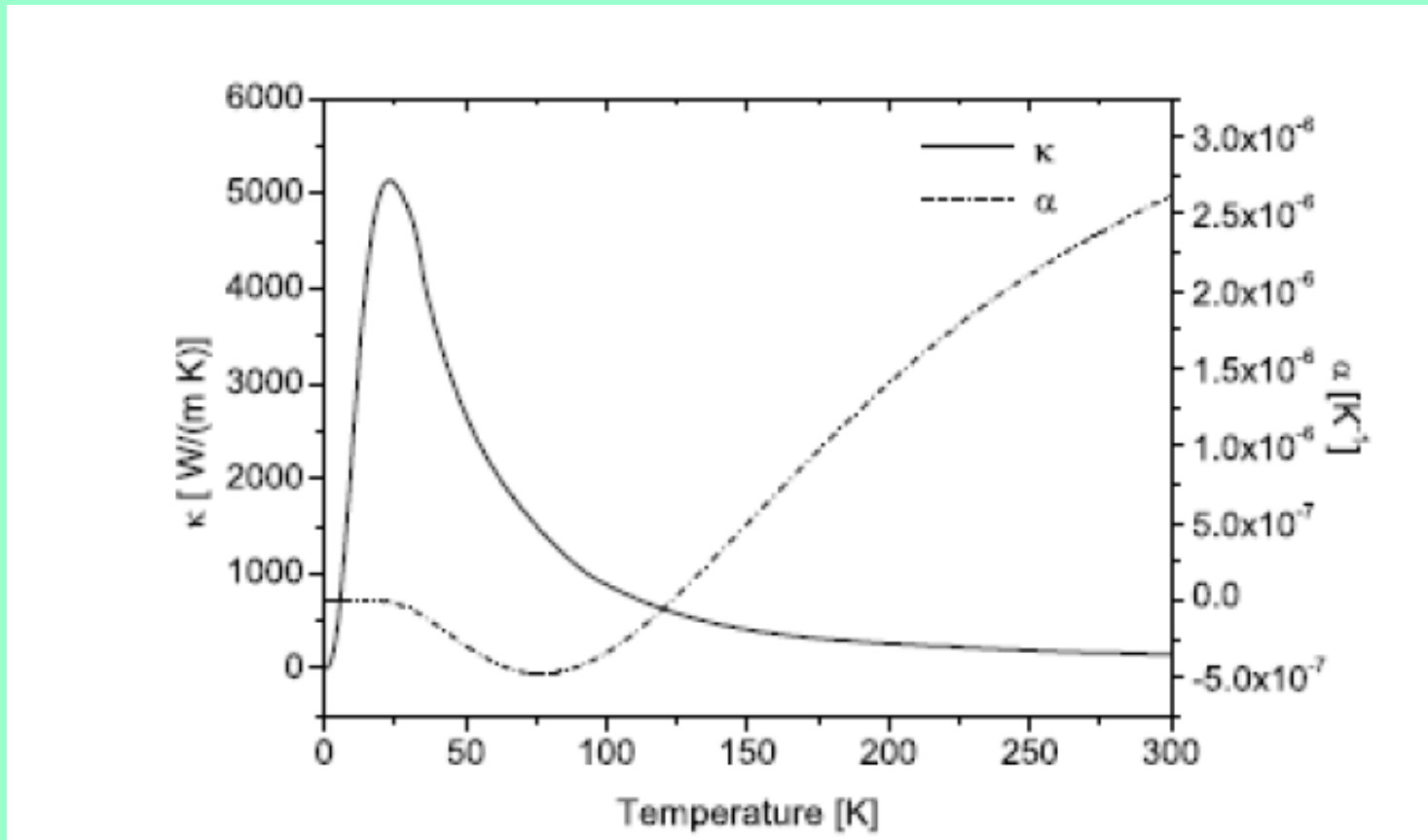
Czochralski

Crystal Rod



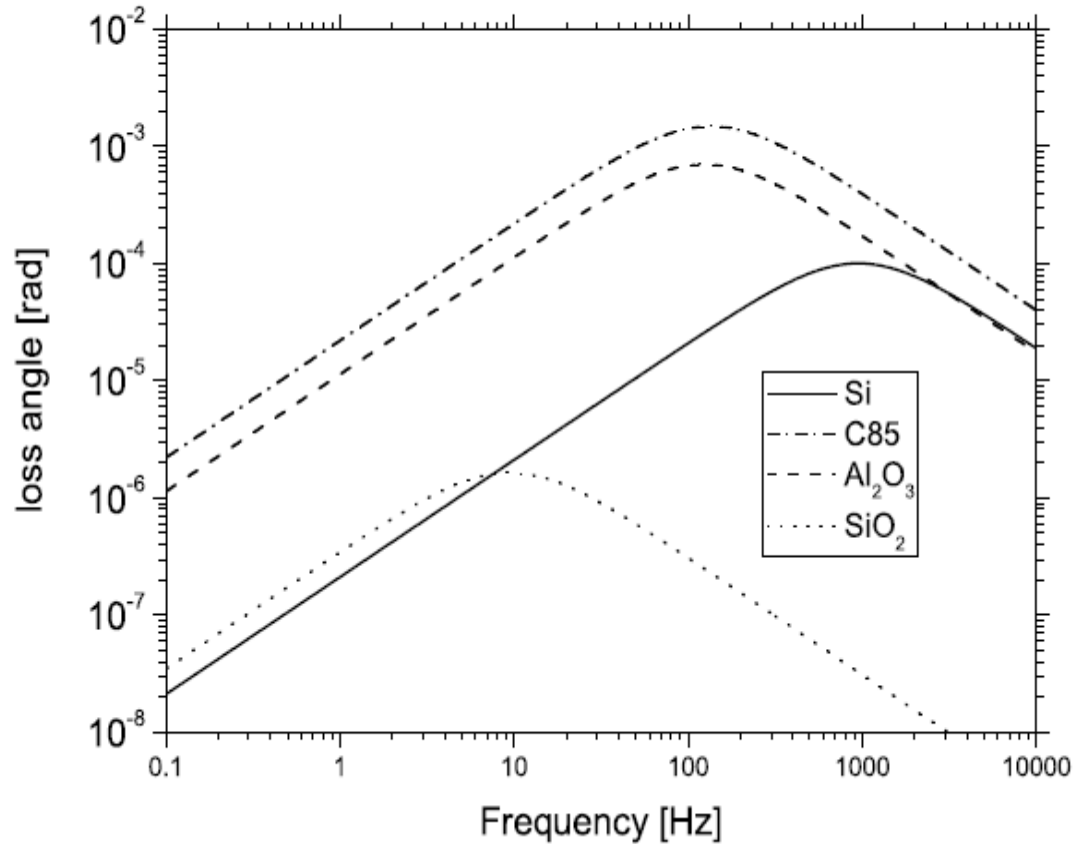
← Monocrystal silicon wire

Silicon crystal physical characteristics



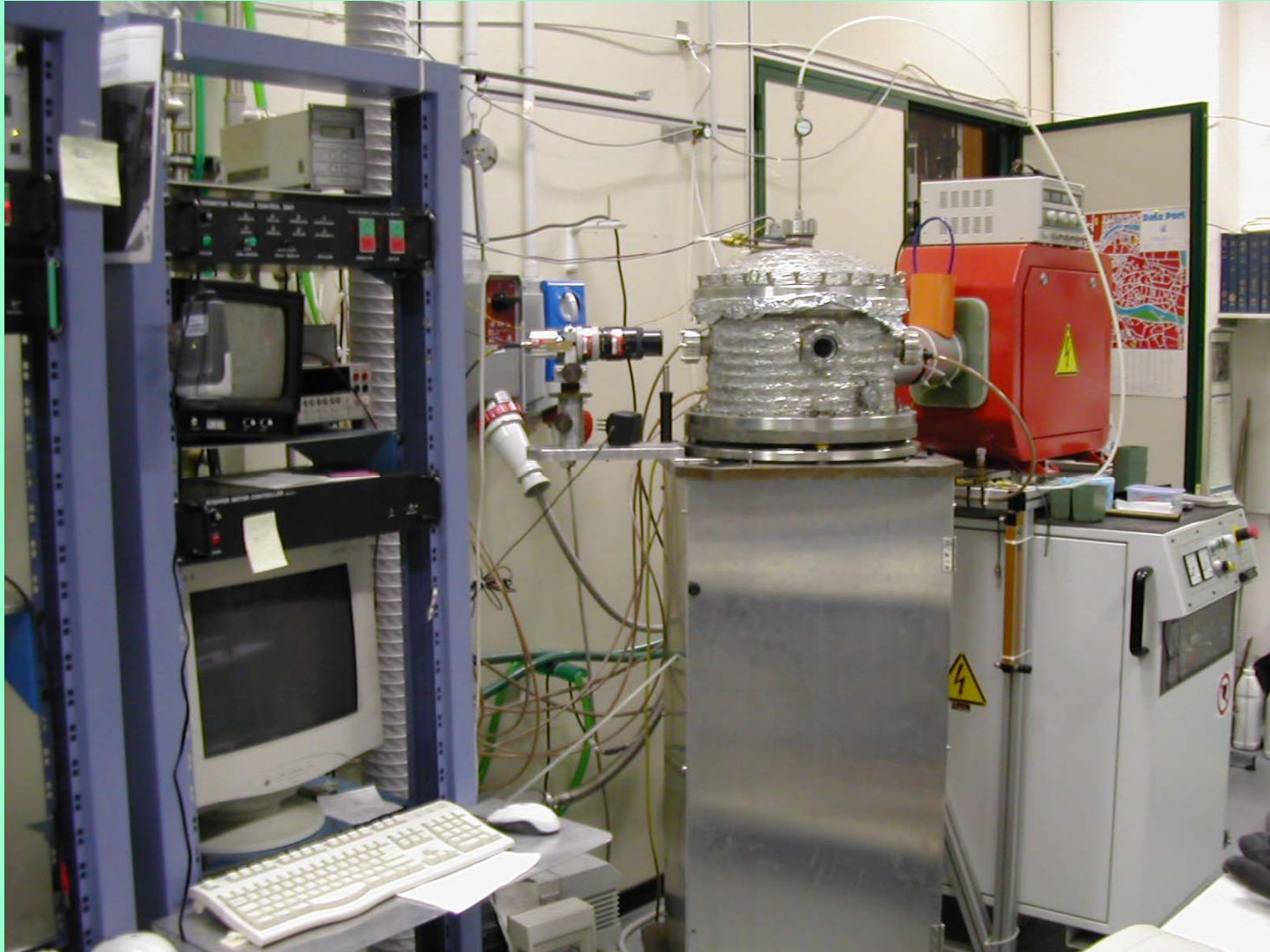
Linear thermal expansion coefficient and Thermal conductivity

Crystal Silicon loss angles

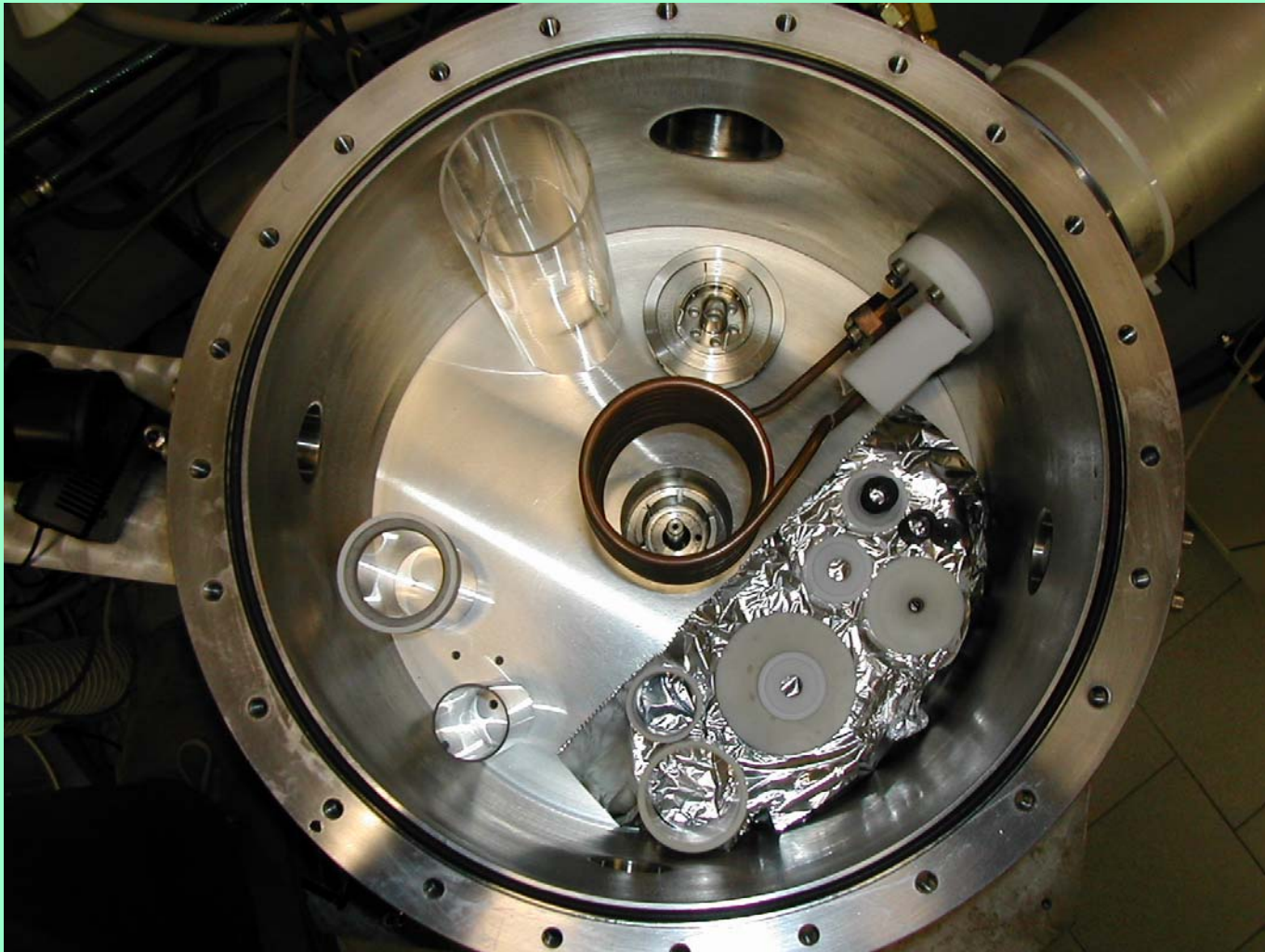


Thermo-elastic loss angles for different materials

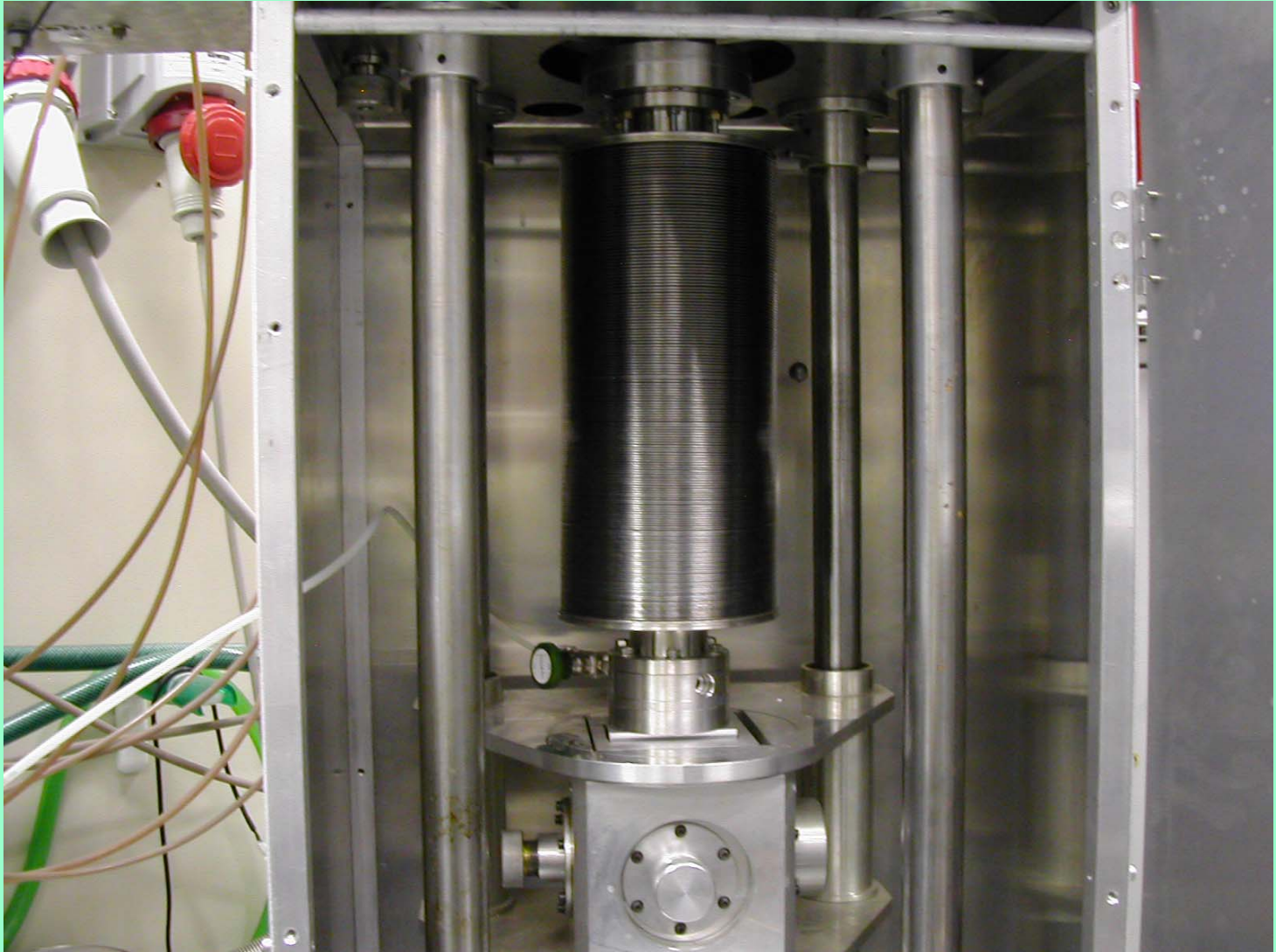
μ -Pd Structure



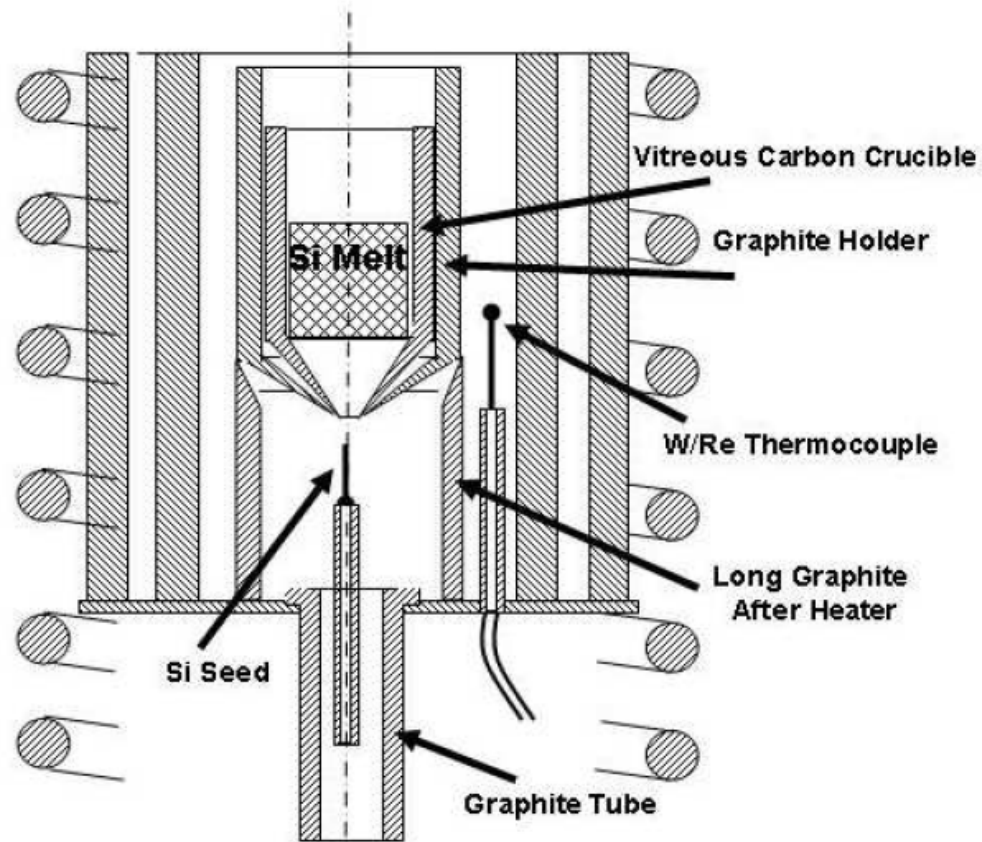
View inside the furnace



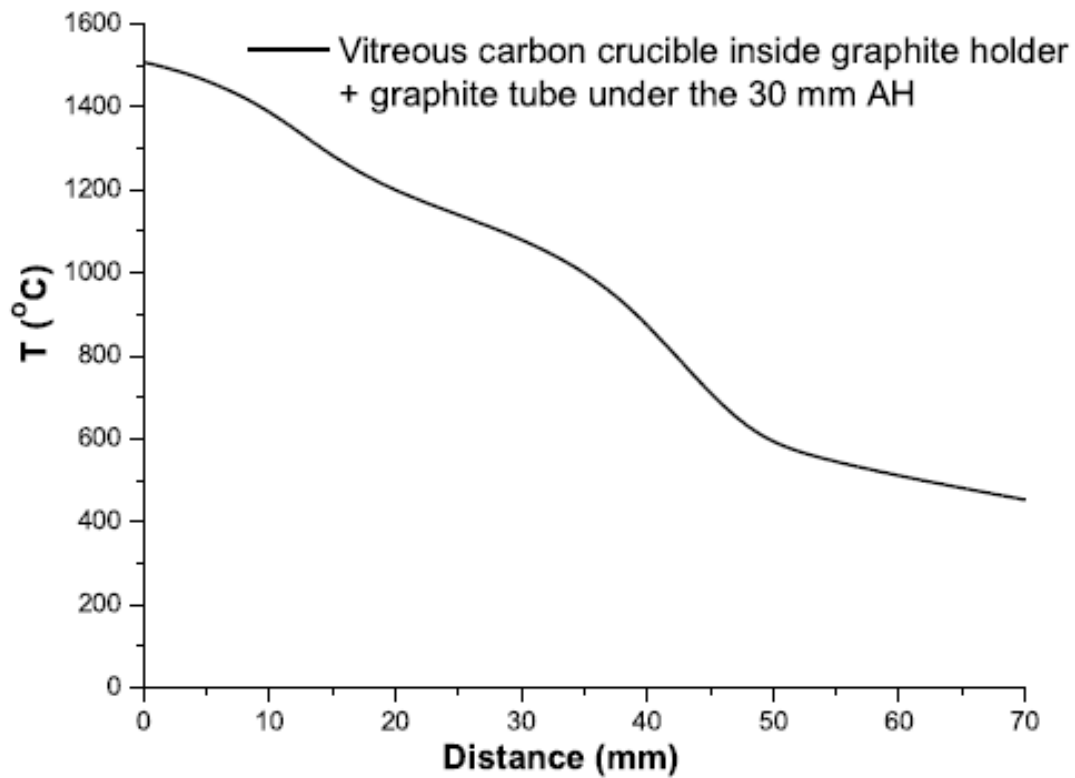
Pulling Structure



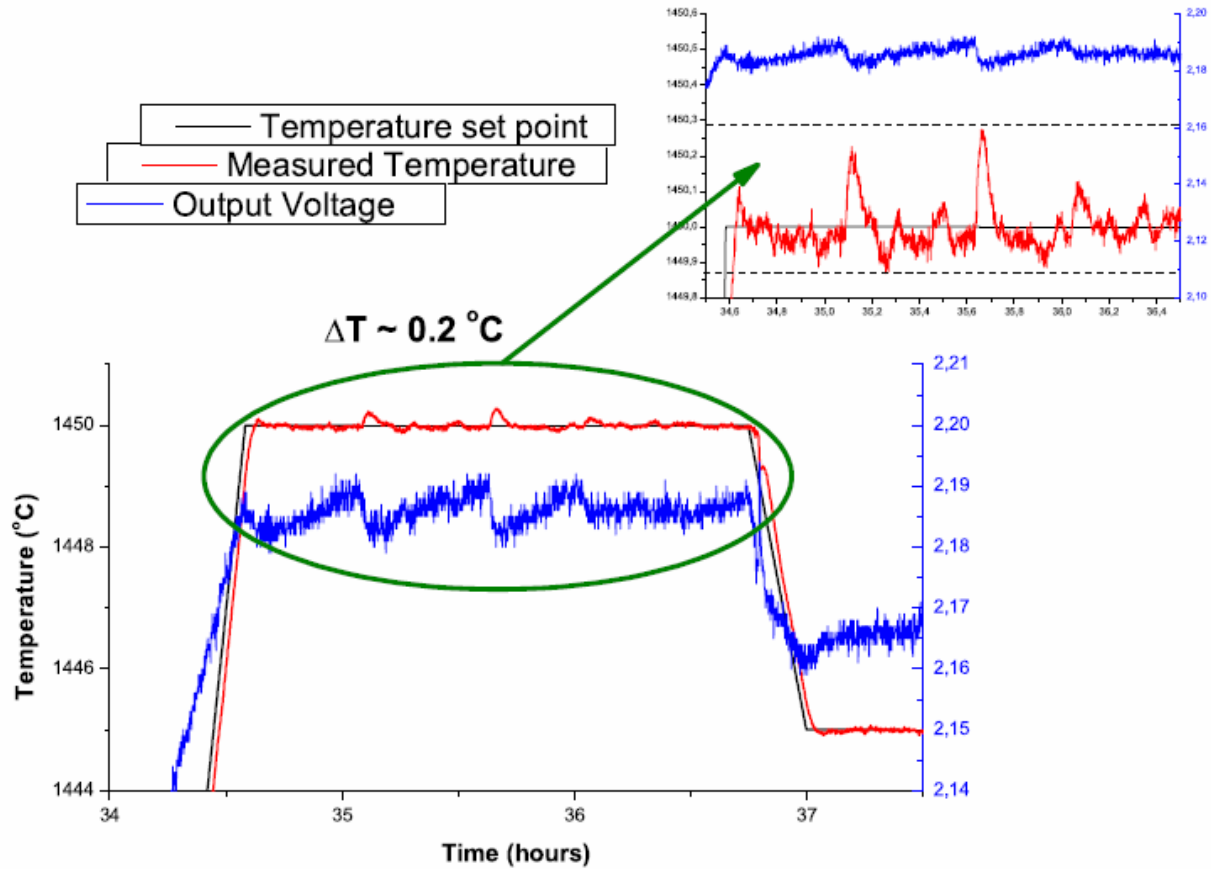
Crucible Assembly



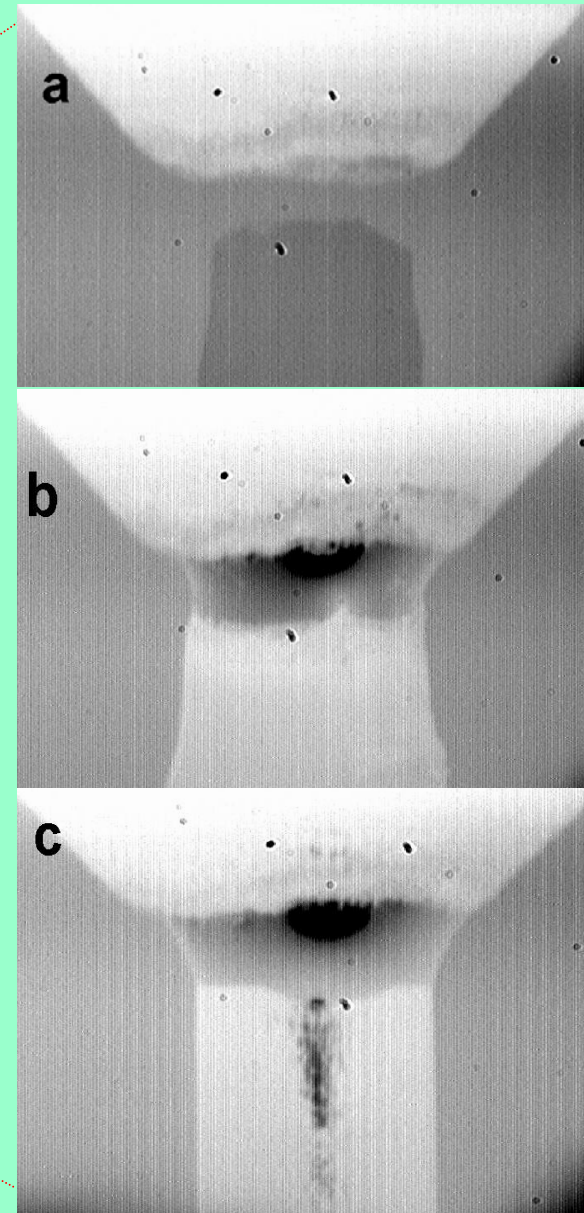
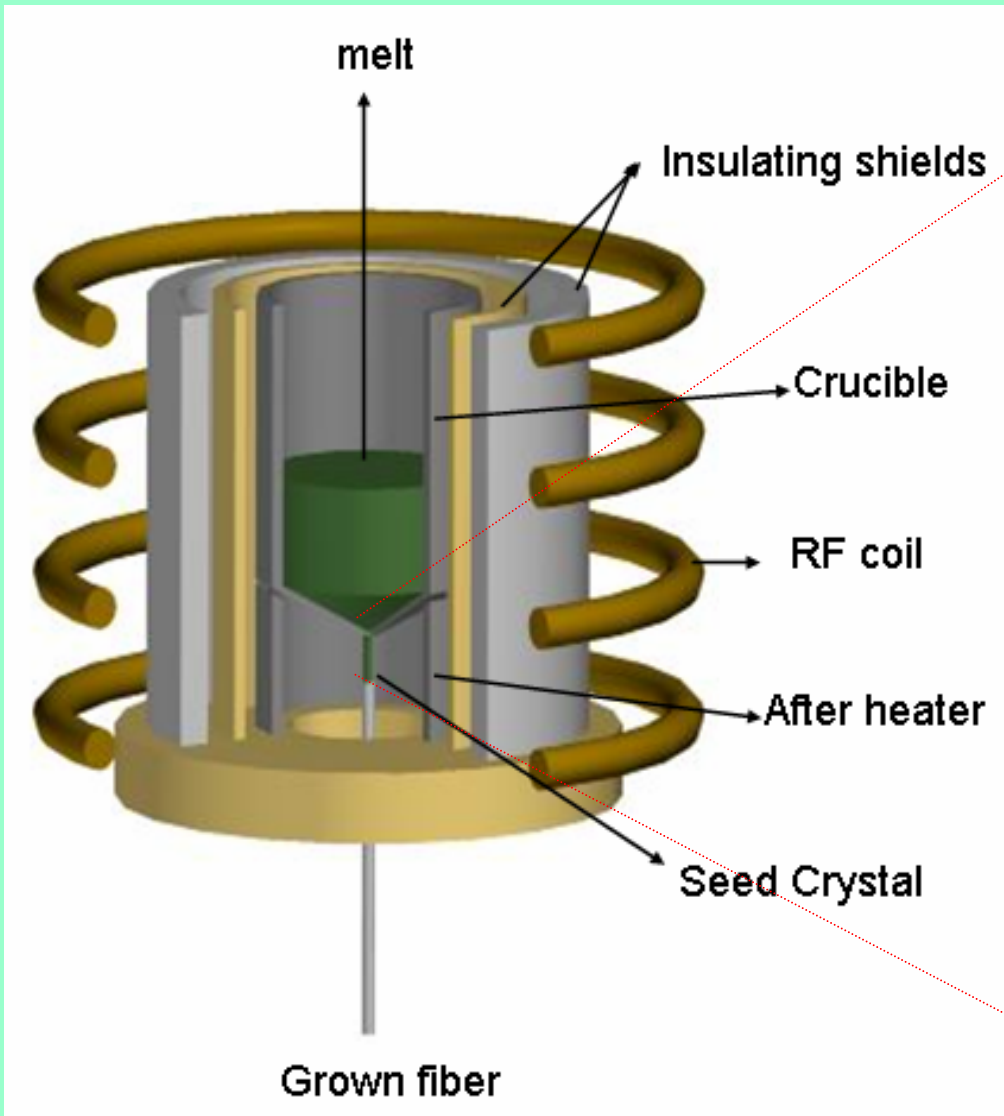
Temperature profile



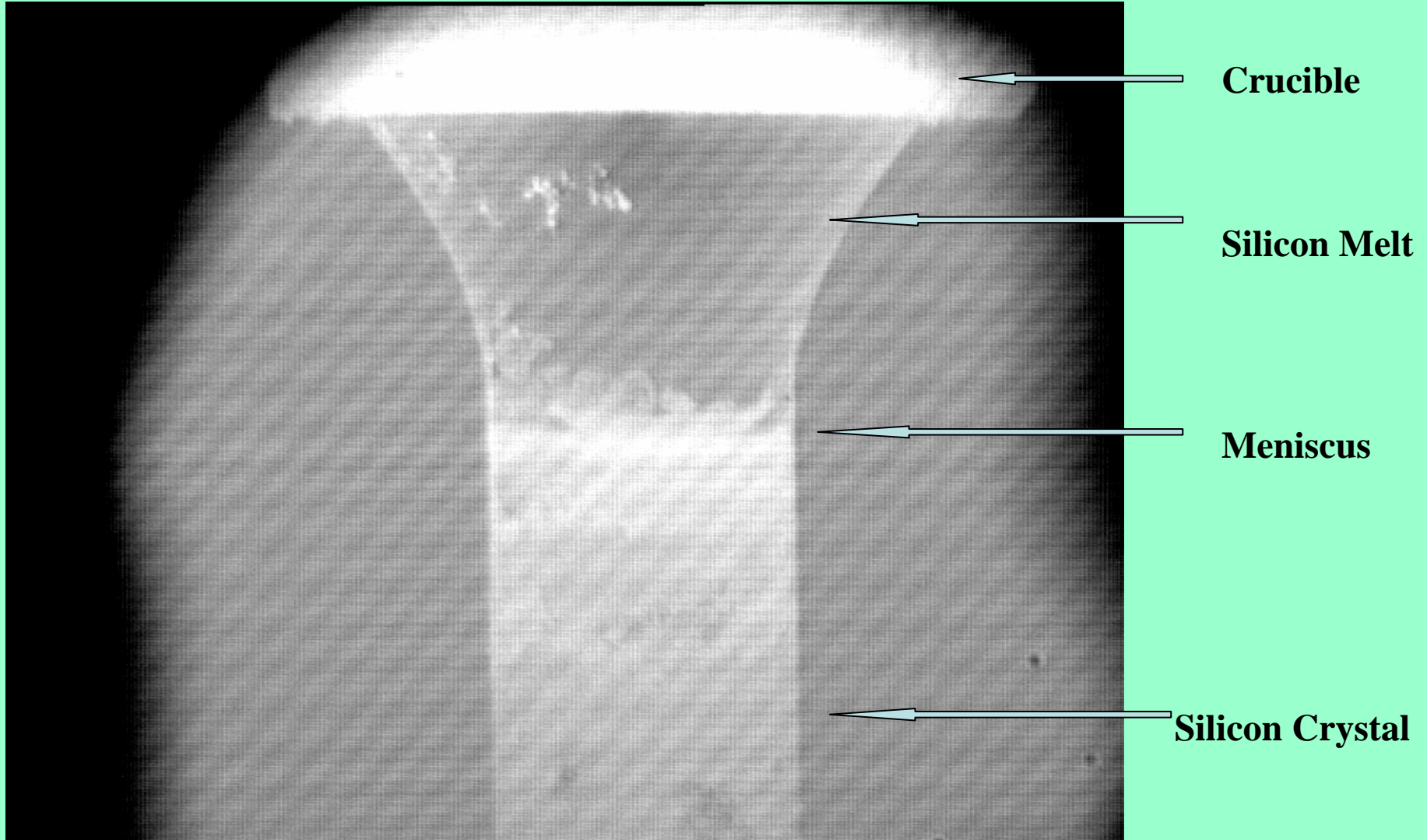
Temperature stability



Schematic of micro-PD method



Fiber growth



Capillary stability

Silicon $\langle 111 \rangle$ $\phi_0 = 11^\circ$

$$dR/dt = v \tan(\phi - \phi_0) \neq 0$$

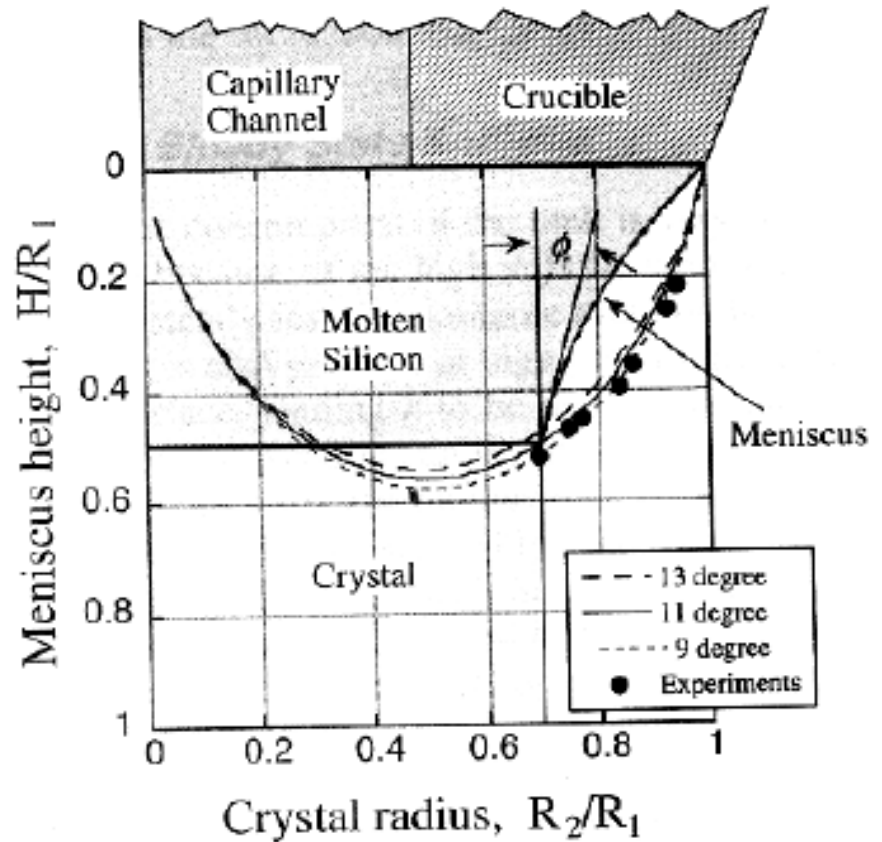
$v = \text{pulling rate}$

Capillarity condition:
Bond number

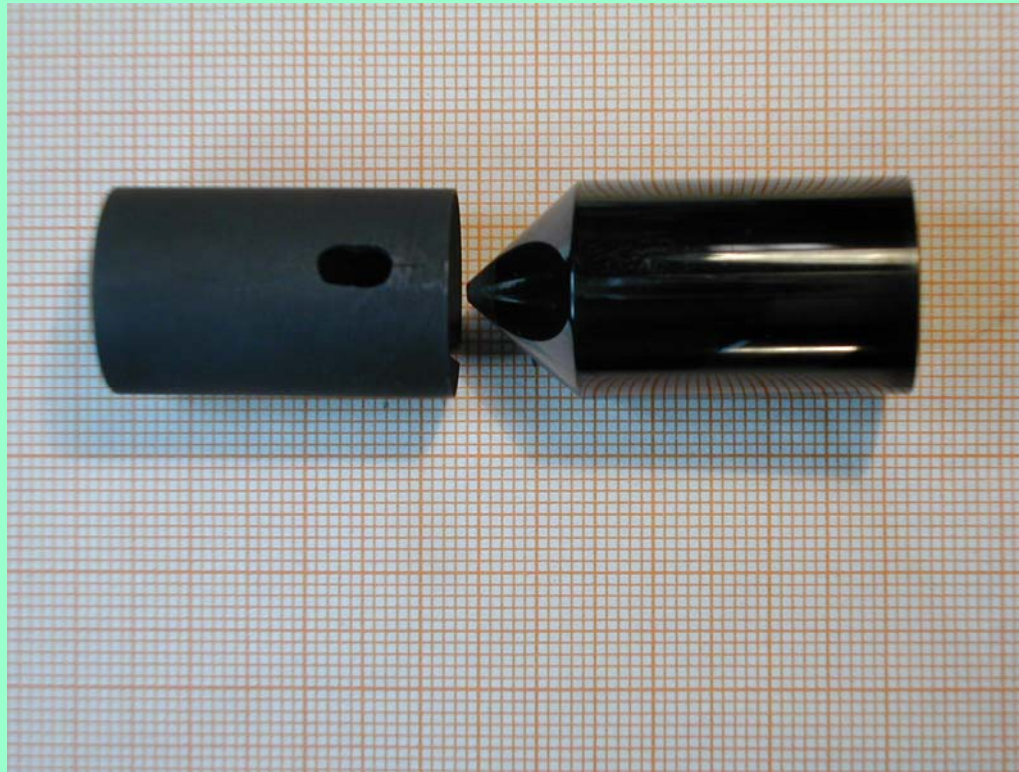
$$B = \rho g d^2 / 4\gamma \ll 1$$

$\rho = \text{melt density}$

$\gamma = \text{surface tension}$



Vitreous carbon crucible



Vitreous carbon crucible and After Heater

Silicon Fiber



As-grown Si Single crystal Fibers with (a) 2.5 mm in diameter and 200 mm long; (b) 1.2 mm in diameter and 210 mm long; (c) 0.7 mm in diameter and 165 mm long

Silicon Fiber



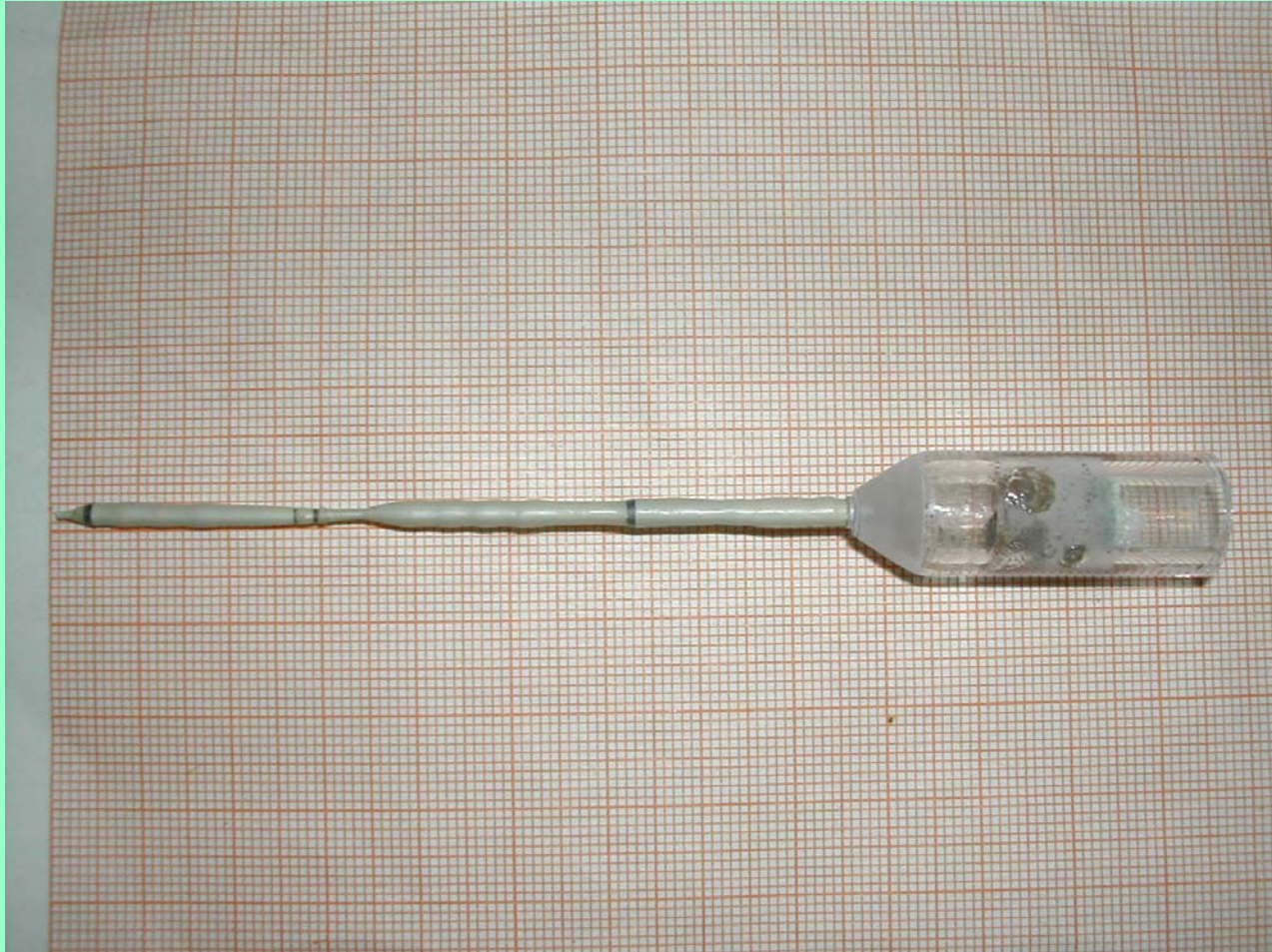
Fiber Diameter ~ 1 mm, Length 290 mm

Silica crucible



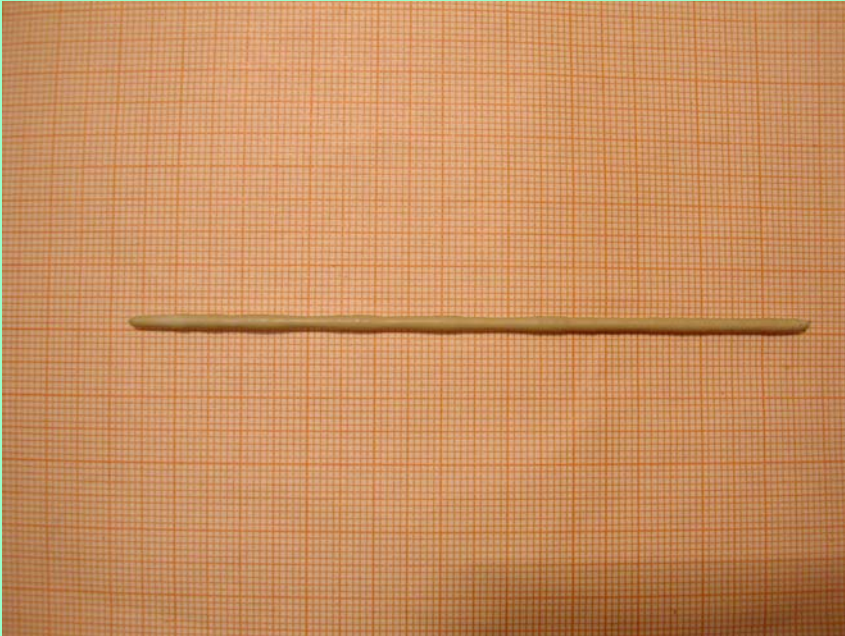
Silica (HQ45) and Special graphite heater

Crucible and silicon fiber

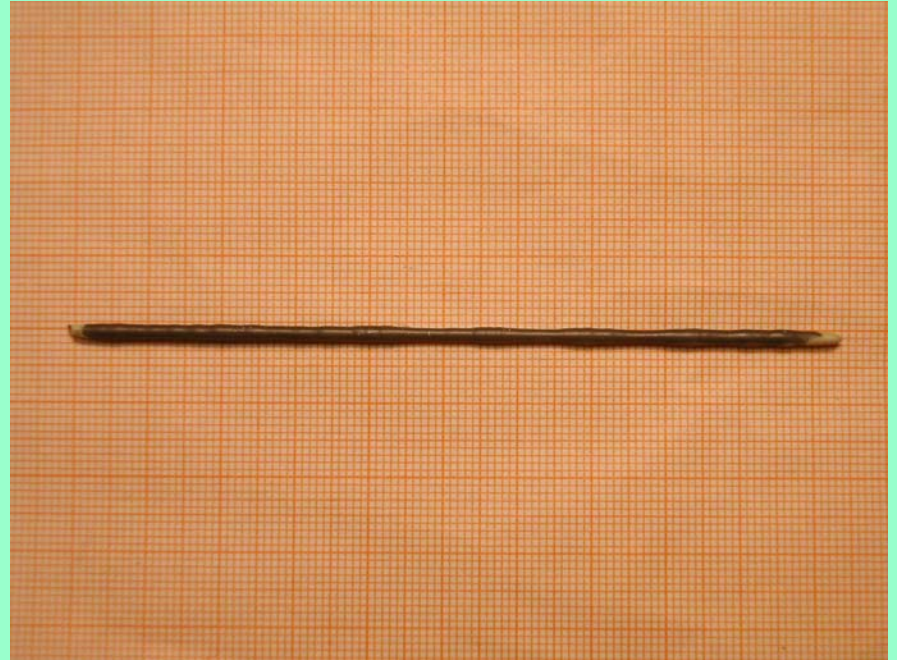


Fiber as grown and Silica Crucible

Silicon Fiber

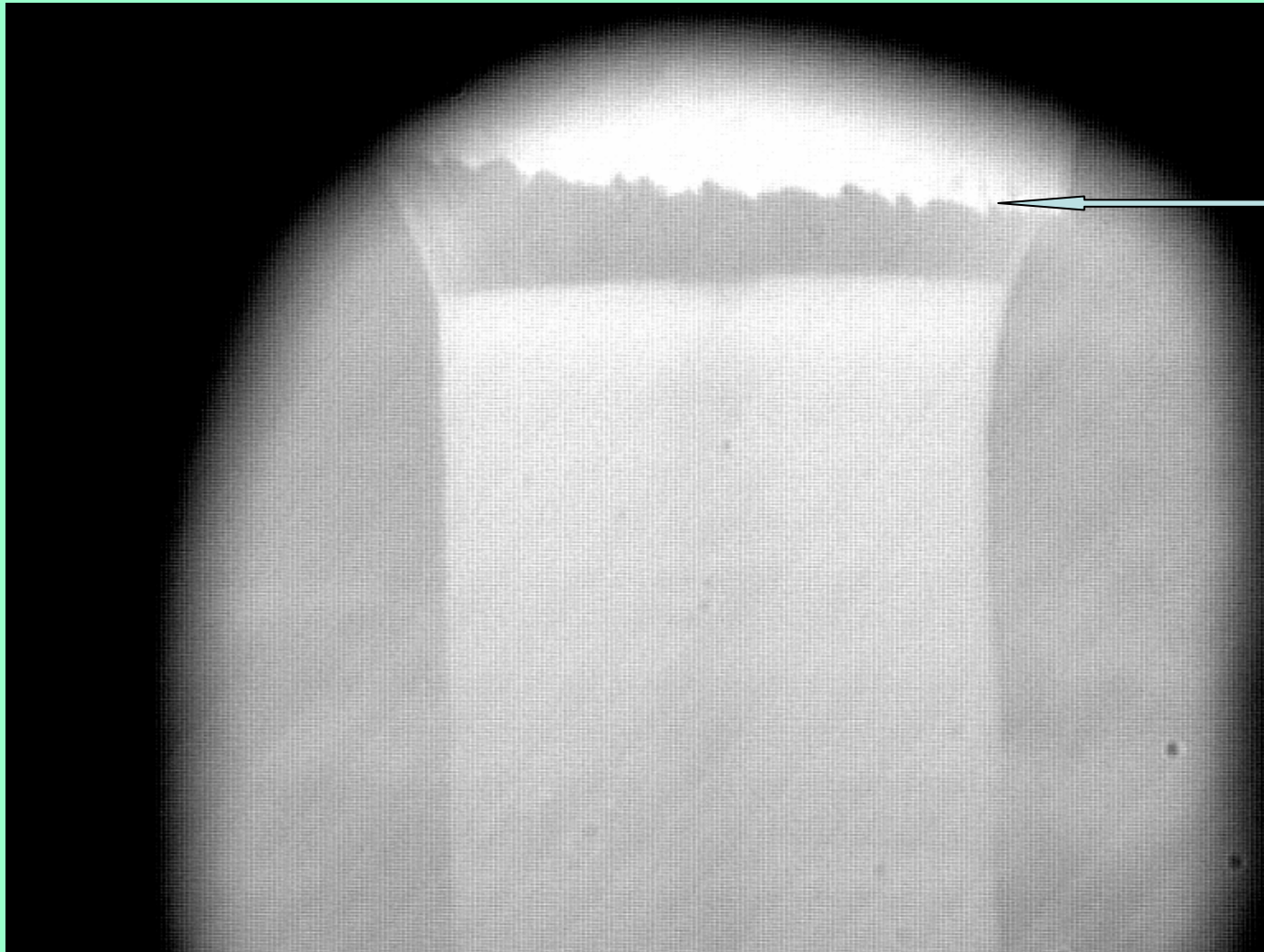


Fiber As grown



Fiber Clean

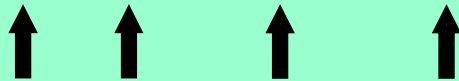
Fiber Growth



**Crucible
damage**



RX-Laue Chamber Analysis

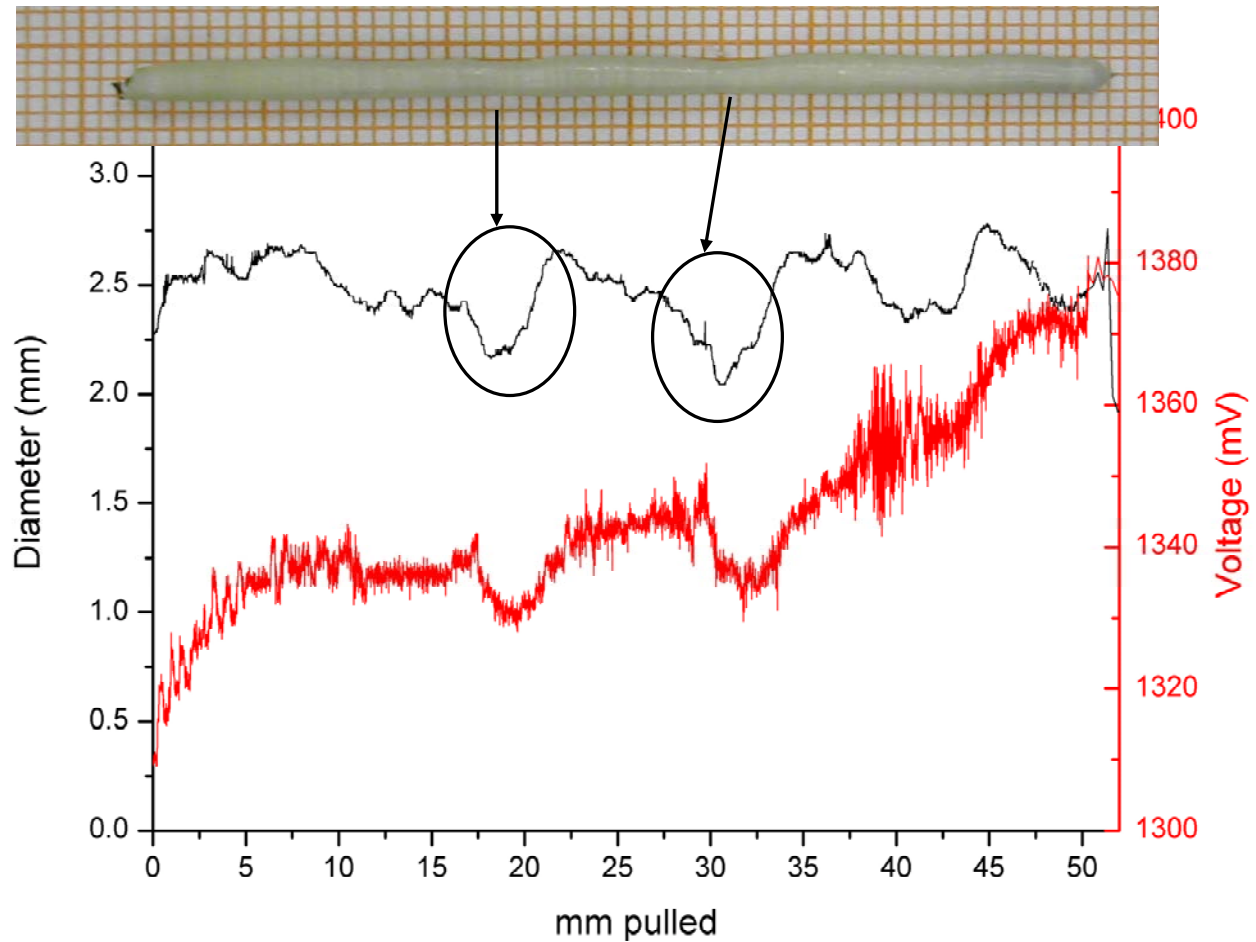


RX-Laue Chamber measurements

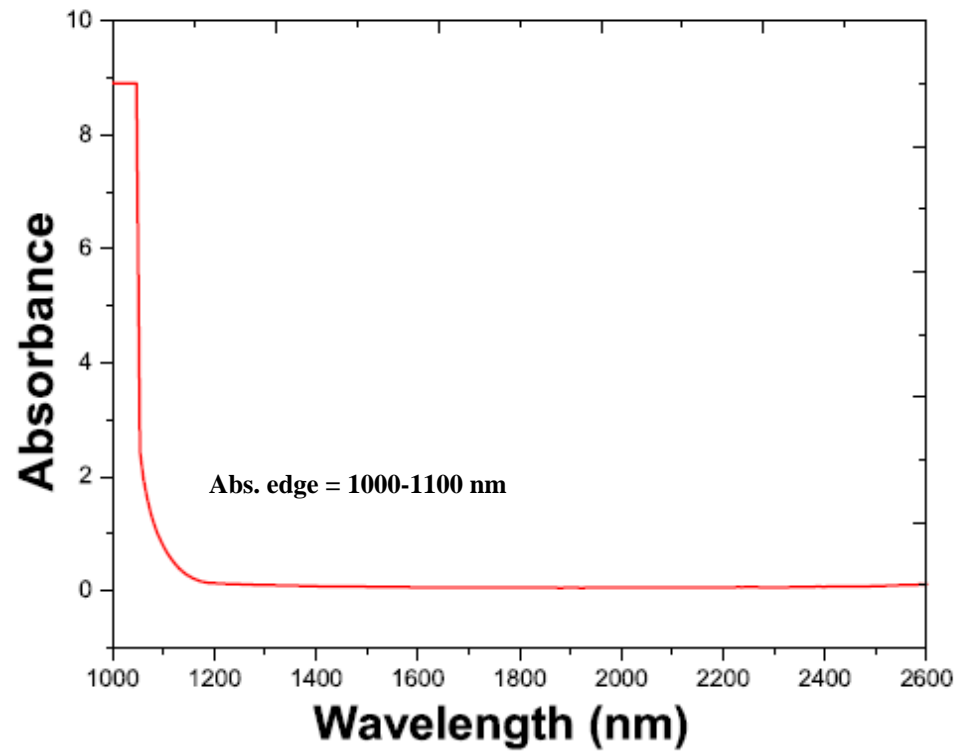


RX diffraction

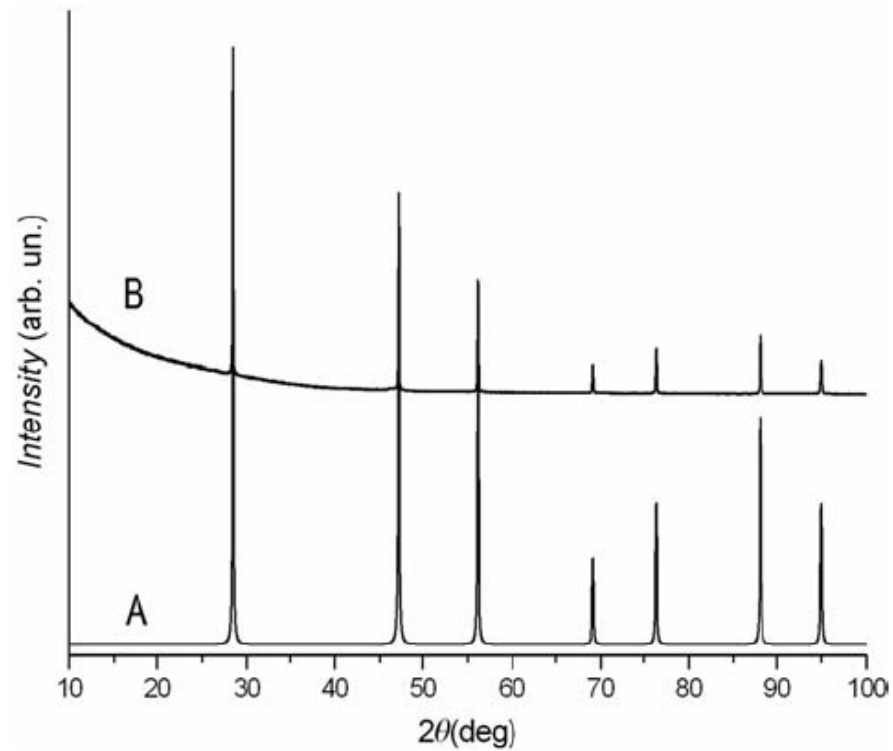
Diameter Fiber Control



Absorption Spectroscopy



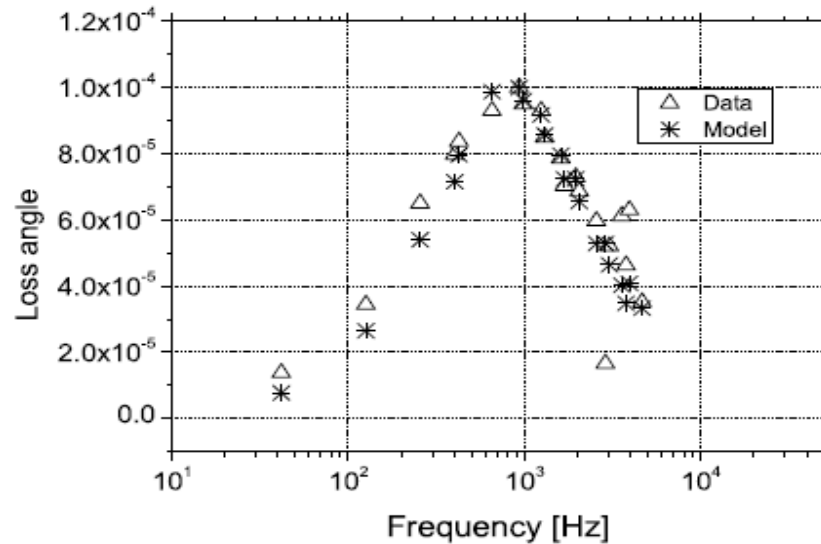
Silicon X-Ray diffraction



Experimental

calculated

Preliminary measurements of loss angle



Problems:

- diameter fluctuation ($\sim 10\%$)
- flip crystal axis orientation (impurities problems)
- clamp problems=chemical bond

Future work

- **Improvement fiber growth**

- **New SiC crucible**

(no chemical reaction with Silicon)

- **FZ Crystal fiber method**

New growth method without crucible contact



Float Zone Fiber Crystal Growth

